

What is superresolution microscopy?

John Bechhoefer^{1, *}

¹*Department of Physics, Simon Fraser University, Burnaby, BC V5A 1S6, Canada*

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I explain what is, is not, and is only sort of superresolution microscopy. I discuss optical resolution, first in terms of diffraction theory, then in terms of linear systems theory, and finally in terms of techniques that use prior information, nonlinearity, and other tricks to improve performance. The discussion reveals two classes of superresolution: Pseudo superresolution techniques improve images up to the diffraction limit but not much beyond. True superresolution techniques allow substantial, useful improvements beyond the diffraction limit. The two classes are distinguished by their scaling of resolution with photon counts. Understanding the limits to imaging resolution involves concepts that pertain to almost any measurement problem, implying that the framework given here has broad application beyond optics.

I. INTRODUCTION

Until the 19th century, it was assumed that improving microscope images was a matter of reducing aberrations by grinding more accurate lenses and by using more sophisticated shapes in their design. In the 1870s, Ernst Abbe¹ (with further contributions by Rayleigh² in 1896 and Porter³ in 1906) came to a radically different conclusion: that wave optics and diffraction posed fundamental limits on the ability to image. These *resolution limits* were proportional to the wavelength λ of light used and pertained to all wave-based imaging.

Beginning in the 1950s, various researchers revisited the question of resolution limits, from the point of view of engineering and linear systems analysis.^{4,5} They noted that traditional discussions of diffraction limits ignored the intensity of images and argued that increasing brightness could, *in principle*, increase resolution beyond the diffraction limit, a phenomenon they termed *superresolution*. The words “in principle” are key, because, *in practice*, such techniques have never led to more than rudimentary demonstrations, although they have given important methods that improve the quality of imaging *near* the diffraction limit.⁶

In the last 20 years, spectacular technological and conceptual advances have led to instruments that routinely surpass earlier diffraction limits, a phenomenon also termed “superresolution.” Unlike the earlier work, these new techniques have led to numerous applications, particularly in biology,⁷ and commercial instruments have begun to appear.⁸ A Nobel prize may be in the offing.

Although the developments in the 1950s and in the last 20 years both concerned “superresolution,” the pace of recent advances makes it obvious that something has changed. I will argue that there are two qualitatively different categories of superresolution techniques, one that gives “pseudo” superresolution and another that leads to “true” superresolution. Sheppard⁹ and Mertz¹⁰ have similarly classified superresolution methods; the somewhat different exposition here was inspired by an example from Harris’s 1964 “systems-style” discussion.¹¹

In the explosion of interest concerning superresolution

techniques, the difference between these categories has sometimes been confused. I hope this article will help clarify the situation. Our discussion will focus on basic concepts rather than the details of specific schemes, for which there are excellent reviews.^{12,13} A long essay by Cremer and Masters gives a detailed and opinionated history of superresolution and shares the view that key concepts have been re-invented or re-discovered many times.¹⁴

The discussion will be framed in terms of a simple imaging problem, that of distinguishing between one point source and two closely spaced ones. In Sec. II, we begin by reviewing the diffraction limit to optics and its role in limiting optical performance. In Sec. III, we discuss optical instrumentation from the point of view of linear-systems theory, where imaging is a kind of low-pass filter, with a resolution that depends on wavelength and signal strength (image brightness). In Sec. IV, we will consider the role of prior expectations in setting resolution. It has long been known that special situations with additional prior information can greatly improve resolution; what is new is the ability to “manufacture” prior expectations that then improve resolution, even when prior information would seem lacking. In Sec. V, we discuss how nonlinearity, by reducing the effective wavelength of light, is another approach to surpassing the classical limits. We will argue that these last two methods, prior engineering and nonlinearity, form a different, more powerful class of superresolution techniques than those based on linear-systems theory. Finally, in Sec. VI, we discuss some of the implications of our classification scheme.

II. RESOLUTION AND THE DIFFRACTION LIMIT

The Abbe limit of resolution is textbook material in undergraduate optics courses.^{15–17} Based on an analysis of wave diffraction that includes the size of lenses and the imaging geometry, it gives the minimum distance Δx

that two objects can be distinguished:¹⁸

$$\Delta x_{\text{Abbe}} = \frac{\lambda}{2n \sin \alpha} \equiv \frac{\lambda}{2 \text{NA}}, \quad (1)$$

where n gives the index of refraction of the medium in which the imaging is done and where α is the maximum angle between the optical axis and all rays captured by the microscope objective. $\text{NA} \equiv n \sin \alpha$ stands for *numerical aperture* and is used to describe the resolution of microscope objectives.¹⁹ A standard trick in microscopy is to image in oil, where $n \approx 1.5$. The resolution improvement relative to air imaging is a factor of n and corresponds to an effective wavelength λ/n in the medium. Well-designed objects can capture light nearly up to the maximum possible angle, $\alpha = \pi/2$. Thus, $\text{NA} = 1.4$ objectives are common and imply a resolution limit of $d \approx 180$ nm, at $\lambda = 500$ nm. With proper sample preparation (to preclude aberrations), modern fluorescence microscopes routinely approach this limit.

To put the ideas of resolution in a more concrete setting, let us consider the problem of resolving two closely spaced point sources. To simplify the analysis, we consider one-dimensional (1d) imaging with incoherent, monochromatic illumination. Incoherence is typical in fluorescence microscopy, since each group emits independently, which implies that intensities add. We also assume an imaging system with unit magnification. Extensions to general optical systems, two dimensions, circular apertures, and coherent light are straightforward.

A standard textbook calculation^{5,15–17} shows that the image of a point source $I_{\text{in}}^{(1)}(x) = \delta(x)$ is the Fraunhofer diffraction pattern of the limiting aperture (exit pupil), which here is just a 1d slit. Figure 1a shows the resulting *point spread function* (PSF):

$$I_{\text{out}}^{(1)}(x) = \left[\text{sinc} \left(\frac{2\pi \text{NA} x}{\lambda} \right) \right]^2 \equiv \text{sinc}(\pi x)^2, \quad (2)$$

where, in the second expression, x is scaled in units of Δx_{Abbe} . We also consider the image formed by two point sources separated by Δx :

$$I_{\text{out}}^{(2)}(x) = \text{sinc} \left[\pi \left(x - \frac{1}{2} \Delta x \right) \right]^2 + \text{sinc} \left[\pi \left(x + \frac{1}{2} \Delta x \right) \right]^2. \quad (3)$$

Figure 1b shows the image of two PSFs separated by $\Delta x = \Delta x_{\text{Abbe}}$, illustrating the intensity profile expected at the classical diffraction limit. The maximum of one PSF falls on the first zero of the second PSF, which also defines the Rayleigh resolution criterion, $\Delta x_{\text{Rayleigh}}$. (With circular lenses, the two criteria differ slightly.) Traditionally, the Abbe/Rayleigh separation between sources defines the diffraction limit. Of course, aberrations and other non-ideal imaging conditions can further degrade the resolution.

III. OPTICS AND LINEAR SYSTEMS

Much of optics operates in the *linear response* regime, where the intensity of the image is proportional to the

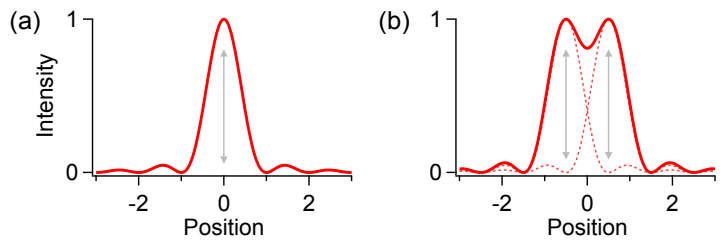


FIG. 1. (a) Isolated point spread function. (b) Two point sources separated by Δx_{Abbe} .

brightness of the source. For an incoherent source, a general optical image is the convolution between the ideal image of geometrical optics and the PSF:

$$I_{\text{out}}(x) = \int_{-\infty}^{\infty} dx G(x - x') I_{\text{in}}(x')$$

$$\tilde{I}_{\text{out}}(k) = \tilde{G}(k) \tilde{I}_{\text{in}}(k), \quad (4)$$

where the integration over $\pm\infty$ is truncated because image and object have finite extent. The tilde indicates Fourier transform, and the second relation is just the convolution theorem. Again, intensities add, not fields.

This *Fourier optics* view was developed by physicists and engineers in the mid-20th century, who sought to understand *linear systems* in general.^{5,20} Lindberg gives a recent review.²¹ One qualitatively new idea is to consider the effects of measurement noise, as quantified by the signal-to-noise ratio (SNR). Let us assume that the intensity of light is set such that a detector, e.g., a pixel in a camera array, records an average of N photons after integrating over a time t . For high-enough light intensities, *shot noise* usually dominates, implying that if $N \gg 1$, the noise measured will be Gaussian, with variance $\sigma^2 = N$.

Since measuring an image yields a stochastic result, the problem of resolving two closely spaced objects can be viewed as a task of *decision theory*: given an image, did it come from one object or two? Of course, maybe it came from three, or four, or even more objects, but it will simplify matters to consider just two possibilities.

A systematic way to decide between scenarios is to calculate their likelihoods, in the sense of probability theory, and to choose the more likely one. Will such a choice be correct? Intuitively, it will if the difference between image models is much larger than the noise. More formally, Harris (1964) calculates the logarithm of the ratio of likelihood functions.¹¹ We thus consider the SNR between

the difference of image models and the noise:

$$\begin{aligned} \text{SNR} &= \frac{1}{\sigma^2} \int_{-\infty}^{\infty} dx \left[I_{\text{out}}^{(1)}(x) - I_{\text{out}}^{(2)}(x) \right]^2 \\ &= \frac{1}{\sigma^2} \int_{-\infty}^{\infty} \frac{dk}{2\pi} \left| \tilde{I}_{\text{out}}^{(1)}(k) - \tilde{I}_{\text{out}}^{(2)}(k) \right|^2 \\ &= \frac{1}{\sigma^2} \int_{-\infty}^{\infty} \frac{dk}{2\pi} \left| \tilde{I}_{\text{in}}^{(1)}(k) - \tilde{I}_{\text{in}}^{(2)}(k) \right|^2 \left| \tilde{G}(k) \right|^2, \quad (5) \end{aligned}$$

where we use Parseval's Theorem in the second line and Eq. (4) in the third. Note that the noise variance σ^2 represents the integrated noise over the entire image.

The Fourier transforms of the input image models are given by $\tilde{I}_{\text{in}}^{(1)}(k) = 1$ and

$$\begin{aligned} \tilde{I}_{\text{in}}^{(2)}(k) &= \int_{-\infty}^{\infty} dx \frac{1}{2} \left[\delta\left(x - \frac{1}{2}\Delta x\right) + \delta\left(x + \frac{1}{2}\Delta x\right) \right] e^{ikx} \\ &= \cos\left(\frac{1}{2}k\Delta x\right). \quad (6) \end{aligned}$$

To calculate the signal-to-noise ratio, we note that intensities are proportional to the photon flux and the integration time t . Since shot noise is a Poisson process, its variance increases linearly in time, and the SNR is proportional to $t^2/t = t$. Using incoherent light implies that $G(x)$ is the intensity response and hence that $\tilde{G}(k)$ is the autocorrelation function of the pupil's transmission function.⁵ For a 1d slit, $\tilde{G}(k)$ is the triangle function, equal to $1 - |k|/k_{\text{max}}$ for $|k| < k_{\text{max}}$ and zero for higher wavenumbers. The cutoff frequency is $k_{\text{max}} = 2\pi/\Delta x_{\text{Abbe}}$. Equation (5) then becomes

$$\text{SNR} \propto t \int_{-k_{\text{max}}}^{k_{\text{max}}} dk \left[1 - \cos\left(\frac{1}{2}k\Delta x\right) \right]^2 (1 - |k|/k_{\text{max}})^2. \quad (7)$$

To compute the SNR for small Δx , consider the limit $k_{\text{max}}\Delta x \ll 1$ and expand the integrand as $[1 - [1 - \frac{1}{2}(\frac{1}{2}k\Delta x)^2 + \dots]]^2 (1 - \dots)^2 \approx [\frac{1}{8}(k\Delta x)^2]^2$. Thus, the SNR $\sim t(k_{\text{max}}\Delta x)^4$, or

$$\Delta x \sim \Delta x_{\text{Abbe}} N^{-1/4}, \quad (8)$$

where we replace time with the number of photons detected N and assume that detection requires a minimum value of SNR, kept constant as N varies. A modest increase in resolution requires a large increase in photon number. The unfavorable scaling explains why the strategy of increasing spatial resolution by boosting spatial frequencies beyond the cutoff cannot increase resolution more than marginally: the signal disappears too quickly as Δx is decreased below Δx_{Abbe} .

The full expression for SNR, Eq. (7), is plotted as Fig. 2, which is normalized to have unity gain for large Δx . We see that the amplitude transfer function for the difference model has the form of a low-pass filter.²² Spatial frequencies below the cutoff are imaged faithfully, but information is severely attenuated when $k > k_{\text{max}}$.

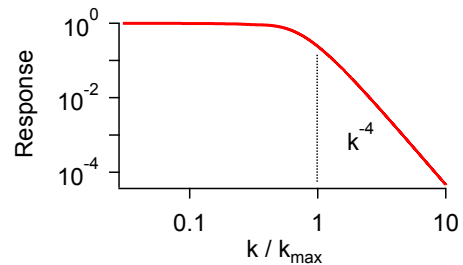


FIG. 2. Modulation transfer function vs. wavenumber, with cutoff frequency $k/k_{\text{max}} \equiv \Delta x_{\text{Abbe}}/\Delta x = 1$ (vertical dotted line).

Although the $N^{-1/4}$ scaling law is supported by the analysis of a specific case, the exponent is generic. Essentially, we distinguish between two possible intensity profiles that have different widths, or, equivalently, between two probability distributions that have different variances. The $-1/4$ exponent in the $N^{-1/4}$ scaling law then reflects a “variance of variance.”²³

If boosting attenuated signals does not lead to significant resolution gains, it can still be very effective in “cleaning up” images and allowing them to approach the standard diffraction limit. Indeed, signal-processing techniques lead to *deconvolution microscopy*, which is a powerful approach to image processing that, with increasing computer power, is now quite practical.⁶ But attempts to use similar techniques to exceed the diffraction limit²⁴—what I call pseudo superresolution—can have only very limited success. The same conclusion pertains to “hardware strategies” that try to modify, or “engineer” the pupil aperture function to reduce the spot size.^{4,25}

A more general way to understand some of the limitations of these classical superresolution approaches is to use *information theory*.^{26,27} One insight that information theory provides is that an optical system has a finite number of *degrees of freedom*, which is proportional to the product of spatial and temporal bandwidths. The number of degrees of freedom is fixed in an optical system, but one can trade off factors. Thus, one can increase spatial resolution at the expense of temporal resolution. This is another way of understanding why collecting more photons can increase resolution.^{9,21,28,29}

IV. SUPERRESOLUTION FROM “PRIOR ENGINEERING”

In the last two decades, conceptual and practical breakthroughs have led to “true” superresolution imaging, where the amount of information that can be recovered from an image by equivalent numbers of photons is greatly increased relative to what is possible in deconvolution microscopy. In this section, we discuss an approach that depends on the manipulation, or “engineering,” of

prior knowledge.

1. Reconstruction using prior knowledge can exceed the Abbe limit

Abbe’s diffraction limit implicitly assumed that there is no significant prior information available about the object being imaged. When there is, the increase in precision of measurements can be spectacular. As a basic example, we consider the *localization* of a single source that we know to be isolated. Here, “localization” contrasts with “resolution,” which pertains to non-isolated sources. This prior knowledge that the source is isolated makes all the difference. If we think of our measurement “photon by photon,” the point-spread function becomes a unimodal probability distribution whose standard deviation σ_0 is set by the Abbe diffraction limit. If we record N photons, then the average has a standard deviation $\approx \sigma_0/\sqrt{N}$, as dictated by the Central Limit Theorem.³⁰ Thus, localization improves with increasing photon counts.³¹ For a typical fluorophore, one can detect $\mathcal{O}(10^4)$ photons, implying localization on the order of a nanometer.³³ Again: localization is not the same as resolution, as it depends on prior information about the source.

2. Reconstruction without prior knowledge fails

We contrast the success in localizing a fluorophore that is known to be isolated with the failure that occurs when we do not know whether the fluorophore is isolated or not. In Sec. III, we considered the problem of distinguishing two sources from one and gave a scaling argument that for separations $\Delta x \ll \Delta x_{\text{Abbe}}$, the number of photons needed to decide between the two scenarios grows too rapidly to be useful. Here, we show more intuitively that the task is hopeless. In Fig. 3, we simulate images from two point sources (Eq. 3) separated by $\Delta x = \frac{1}{2}\Delta x_{\text{Abbe}}$. The markers show the number of photon counts for each spatial bin (camera pixel), assuming measurements are shot noise limited. Error bars are estimated as the square root of the number of counts in this Poisson process.³⁴ In Fig. 3a, there are ≈ 100 photon counts recorded. A fit to a *single* source, of unknown position and strength and width fixed to that of the PSF has a χ^2 statistic that cannot be ruled out as unlikely. The only way to distinguish between two sources and a single source would be to compare its amplitude to that of a single source, but sources can have different strengths: Different types of fluorophores obviously do, but even a single type of fluorophore, when immobilized on a surface for imaging, has an orientational dependence that influences its emission strength.^{36,37}

Increasing the counts to ≈ 1000 (Fig. 3b) allows one to rule out a single source, as the width now exceeds that of the PSF by a statistically significant amount. (Note the

smaller error bars for each point.) Still, the disagreement is subtle, at best: Reliable inference is unlikely without sufficient prior information.

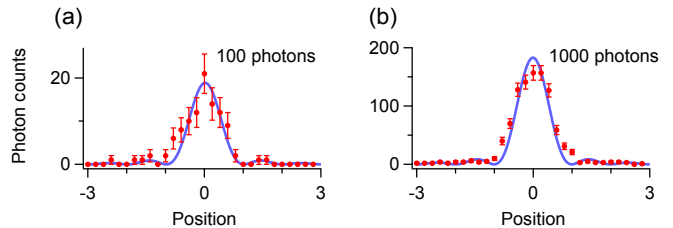


FIG. 3. Two sources or one? (a) and (b) simulate two sources located at $x = \pm 0.25$. Each PSF has width = 1. Markers show photon counts N_i in each bin (pixel), with error bars equal to $\sqrt{N_i}$. (a) 100 photons. $\chi^2 = 14.2$ for $\nu = 14$ degrees of freedom. (b) 1000 photons. $\chi^2 = 120$ for $\nu = 27$. The range $[-3, 3]$ is divided into 30 bins.

3. PALM and STORM: engineering the prior

Recently, two groups independently developed a technique that gives the precision of single-source localization microscopy without the need for *a priori* knowledge of localization. The technique is known as PALM (Photo-Activated Localization Microscopy³⁸) or STORM (Stochastic Optical Reconstruction Microscopy³⁹), and they share the idea of making nearby molecules *different*, so that they can be *separately* localized. One way to differentiate neighboring fluorophores is that some types of fluorescent groups are dark until photo-activated, usually by blue or UV light.⁴⁰ Once active, the molecules may be excited fluorescently using lower-wavelength light. Once excited, they fluoresce at a still-lower wavelength. Thus, PALM/STORM proceeds as follows: A weak light pulse activates a *sparse subset* of fluorophore molecules. Each of these now-separated sources is then localized, as for isolated molecules. After localization, a strong excitation pulse photobleaches the active molecules, making them permanently dark. Another activation pulse then turns on a different sparse subset, which is subsequently localized. Repeating this cycle many times builds up an image whose sources are very close to each other. The trick is to sequentially activate the sources, so that they are isolated while being interrogated.⁴¹

Thus, clever “engineering” of prior expectations can give the benefits of localization microscopy, even when sources are not well-separated. The precision is increased by \sqrt{N} over the classical diffraction limit, where N is the average number of photons recorded from the isolated point sources.

V. SUPERRESOLUTION FROM NONLINEARITY

While PALM/STORM is computationally based, an alternate technique known as STED (STimulated Emission Depletion) microscopy is “hardware based.” The idea was proposed in 1994 by Hell and Wichmann⁴³ and then extensively developed in the former’s group, along with a set of closely related methods.¹²

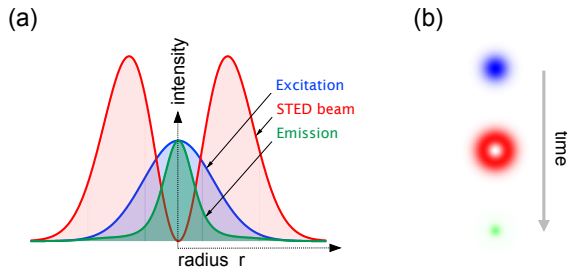


FIG. 4. Illustration of STED imaging. (a) 1d cut through intensity profile, illustrating the broad excitation pulse (blue), the doughnut-shaped STED depletion beam (red), and the narrow emission pulse (green). (b) 2d beam profiles showing the temporal sequence of beams.

The basic idea of STED is illustrated in Fig. 4. A picosecond (ps)-scale conventional focussed spot excites fluorescence in a spot (blue). The width of this beam (in the sample plane) has a scale set by the Abbe limit, $\lambda/(2NA)$. The excitation beam is followed by the ps-scale STED beam (red) a few ps after the original excitation pulse. The timing ensures that the excited fluorescent molecules have not had time to decay. (Their lifetime \approx ns.) Because the STED beam has a dark spot at its center, it de-excites the original beam “from the outside in,” using stimulated emission. The distribution of surviving excited molecules then has a reduced width. When they eventually decay, they are detected by their ordinary fluorescence emission (green). The result is equivalent to a narrower excitation beam. The reduced size of the point-spread function implies higher resolution.

The width of the emission PSF is given by⁴⁴

$$\Delta x_{\text{STED}} = \frac{\Delta x_{\text{Abbe}}}{\sqrt{1 + I_{\text{STED}}/I_{\text{sat}}}}. \quad (9)$$

For $I_{\text{STED}} \gg I_{\text{sat}}$, $\Delta x_{\text{STED}} \sim I_{\text{STED}}^{-1/2} \sim \Delta x_{\text{Abbe}} N^{-1/2}$, where N is the number of photons detected. The resolution improvement has the same scaling with photon counts as does PALM/STORM (or localization in general). Both are qualitatively better than the scaling for deconvolution microscopy.

We derive Eq. (9) following Harke et al.⁴⁴ The 1d-excitation PSF in the sample plane is approximately $h_{\text{exc}}(x) \sim e^{-x^2/2}$, in units of Δx_{Abbe} . We can approximate the STED beam intensity near the center by its quadratic expansion, so that $I_{\text{STED}}(x) \sim$

$\frac{1}{2}(I_{\text{STED}}/I_{\text{sat}})x^2$. After the STED pulse, the fraction of surviving molecules in the original pulse is $\eta(x) \sim e^{-\frac{1}{2}(I_{\text{STED}}/I_{\text{sat}})x^2}$. Thus,

$$h(x) \sim h_{\text{exc}}(x)\eta(x) \sim e^{-\frac{1}{2}[1+(I_{\text{STED}}/I_{\text{sat}})]x^2} \equiv e^{-\frac{1}{2}(x^2/\Delta x_{\text{STED}})^2}, \quad (10)$$

which leads directly to Eq. (9).

Why is there a fundamental improvement in resolution? STED is a nonlinear technique: the fluorophore response is quantized into a few possibilities, rather than responding linearly, as it would in a classical world. Nonlinearity also occurs in the exponential survival probability $\eta(x)$. With a purely linear response, no resolution enhancement would be possible, since the spatial scale of the STED beam is also subject to the Abbe limit and must thus vary on the same length scale as the original excitation beam.

STORM/PALM and STED are just two among many techniques for fundamentally surpassing the classical diffraction limit. For want of space, we omit discussion of many other ways to surpass the Abbe limit, including pseudo superresolution techniques such as confocal imaging,⁴⁵ multiphoton microscopy,⁴⁶ and 4Pi-microscopy^{47,48}; true superresolution techniques such as near-field scanning (NSOM),^{49–51} multiple scattering (which converts evanescent modes into propagating ones),⁵² saturation microscopy,^{53,54} and the “perfect imaging” promised by metamaterials.^{55,56} Some techniques, such as structured illumination,^{57,58} are hard to classify because they contain elements of both types of superresolution.

VI. CONCLUSION AND IMPLICATIONS

Superresolution microscopy techniques divide into two broad classes:

- Pseudo superresolution, based on deconvolution microscopy and other ideas of linear systems theory, which aims to make maximum use of the available information, using minimal prior expectations. The general idea is to use the known, or estimated optical transfer function to boost the measured signal back to its original level. The ability to do so is limited by measurement noise. The poor scaling, $\Delta x \sim N^{-1/4}$, implies a resolution only slightly beyond the standard diffraction limit.
- True superresolution, which increases the amount of recoverable information, for example by creating prior information (stochastic reconstruction methods) or nonlinear tricks, such as those used in STED. Resolution scales as $\Delta x \sim N^{-1/2}$, a much more favorable law that allows significant increases in resolution, in practical situations.

The classification of superresolution presented here is general and applies beyond optics. To list just one example, there is good evidence⁵⁹ that humans can resolve musical pitch much better than the classic time-frequency uncertainty principle, which states that the product $\Delta t \Delta f \geq \frac{1}{4\pi}$, where Δt is the time a note is played and Δf the difference in pitch to be distinguished. Since humans can routinely beat this limit, Oppenheim and Magnasco conclude that the ear and/or brain must use nonlinear processing.⁵⁹ But louder sounds will also improve pitch resolution, in analogy with our discussion of light intensity and low-pass filtering, an effect they do not discuss. Whether “audio superresolution” is due to high signal levels or to nonlinear processing, the ideas presented are perhaps useful for understanding the limits

to pitch resolution.

The questions about superresolution that we have explored here in the context of microscopy (and, briefly, human hearing) apply in some sense to any measurement problem. Understanding what limits measurements—appreciating the roles of signal-to-noise ratio and of prior expectations—should thus be part of the education of a physicist.

ACKNOWLEDGMENTS

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- * johnb@sfu.ca
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 - ⁵ Joseph W. Goodman, *Introduction to Fourier Optics*, 3rd ed. (Roberts and Company Publishers, 2005). The first edition was published in 1968.
 - ⁶ Jean-Baptiste Sibarita, “Deconvolution microscopy,” *Adv. Biochem. Engin. / Biotechnol.* **95**, 201–243 (2005).
 - ⁷ Bonnie O. Leung and Keng C. Chou, “Review of superresolution fluorescence microscopy for biology,” *Appl. Spect.* **65**, 967–980 (2011).
 - ⁸ For example, a STED microscope is sold by the Leica Corporation.
 - ⁹ Colin J. R. Sheppard, “Fundamentals of superresolution,” *Micron* **38**, 165–169 (2007). Sheppard introduces three classes rather than two: *Improved* superresolution boosts spatial frequency response but leaves the cutoff frequency unchanged. *Restricted* superresolution includes tricks that increase the cut-off by up to a factor of two. We use “pseudo” superresolution for both cases. Finally, *unrestricted* superresolution refers to what we term “true” superresolution.
 - ¹⁰ Jerome Mertz, *Introduction to Optical Microscopy*, (Roberts and Co., 2010), Ch. 18. Mertz follows Sheppard’s classification, giving a simple but broad overview.
 - ¹¹ J. L. Harris, “Resolving power and decision theory,” *J. Opt. Soc. Am.* **54**, 606–611 (1964).
 - ¹² Stefan W. Hell, “Far-field optical nanoscopy,” *Springer Series in Chemical Physics* **96**, 365–398 (2010).
 - ¹³ Bo Huang, Hazen Babcock, and Xiaowei Zhuang, “Breaking the diffraction barrier: superresolution imaging of cells,” *Cell* **143**, 1047–1058 (2010).
 - ¹⁴ Christoph Cremer and Barry R. Masters, “Resolution enhancement techniques in microscopy,” *Eur. Phys. J. H* **38**, 281–344 (2013).
 - ¹⁵ Eugene Hecht, *Optics*, 4th ed. (Addison-Wesley, 2002), Ch. 13.
 - ¹⁶ Geoffrey Brooker, *Modern Classical Optics* (Oxford Univ. Press, 2002), Ch. 12.
 - ¹⁷ Ariel Lipson, Stephen G. Lipson, and Henry Lipson, *Optical Physics*, 4th ed. (Cambridge Univ. Press, 2011), Ch. 12. This edition of a well-established text adds a section on superresolution techniques, with a view that complements the one presented here.
 - ¹⁸ Equation (1) gives the *lateral* resolution. The resolution along the optical axis is poorer: $d = \frac{\lambda}{n \sin^2 \alpha}$.
 - ¹⁹ However, the magnification of an objective does not determine its resolution.
 - ²⁰ P. M. Duffieux, *The Fourier Transform and Its Applications to Optics*, 2nd ed. (John Wiley & Sons, 1983). The first edition, in French, was published in 1946. Duffieux formulated the idea of the optical transfer function in the 1930s.
 - ²¹ Jari Lindberg, “Mathematical concepts of optical superresolution,” *J. Opt.* **14**, 083001 (23pp) (2012).
 - ²² A subtle point: the modulation transfer function is zero beyond a finite spatial frequency; yet the response in Fig. 2 is non-zero at all frequencies. The explanation is that an object of finite extent has a Fraunhofer diffraction pattern (Fourier transform) that is *analytic*, neglecting noise. Analytic functions are determined by any finite interval (analytic continuation), meaning that one can, in principle, extrapolate the bandwidth and deduce the exact behavior beyond the cutoff from that inside the cutoff. In practice, noise cuts off the information (Fig. 2). See Lucy²³ for a brief discussion and⁵ for more detail.
 - ²³ L. B. Lucy, “Statistical limits to superresolution,” *Astron. Astrophys.* **261**, 706–710 (1992). Lucy does not assume the PSF width to be known and thus reaches the more pessimistic conclusion that $\Delta x \sim N^{-1/8}$. Since the second moments are then matched, one has to use the variance of the fourth moment to distinguish the images.
 - ²⁴ Kevin Piché, Jonathan Leach, Allan S. Johnson, Jeff. Z. Salvail, Mikhail I. Kolobov, and Robert W. Boyd, “Experimental realization of optical eigenmode superresolution,”

- Opt. Exp. **20**, 26424 (2012). Instruments with finite aperture sizes have discrete eigenmodes (that are not simple sines and cosines), which should be used for more accurate image restoration.
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- ²⁶ G. Toraldo di Francia, “Resolving power and information,” *J. Opt. Soc. Am.* **45**, 497–501 (1955).
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